

A compact, low-field, broadband matching section for externallypowered X-band dielectric-loaded accelerating structures

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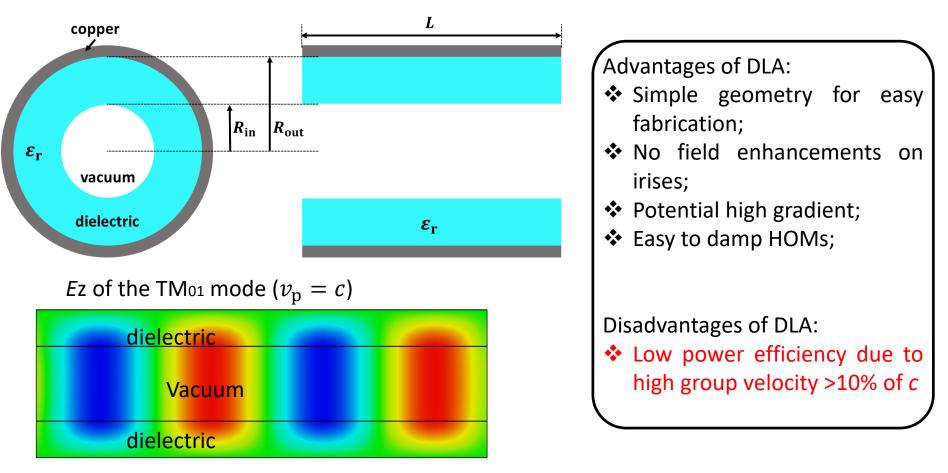
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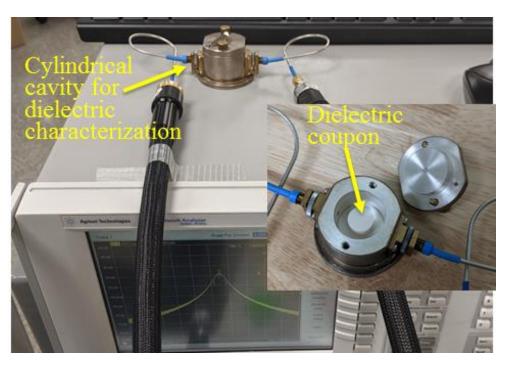
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Introduction

• Slow wave accelerators: dielectric-loaded accelerating (DLA) structures



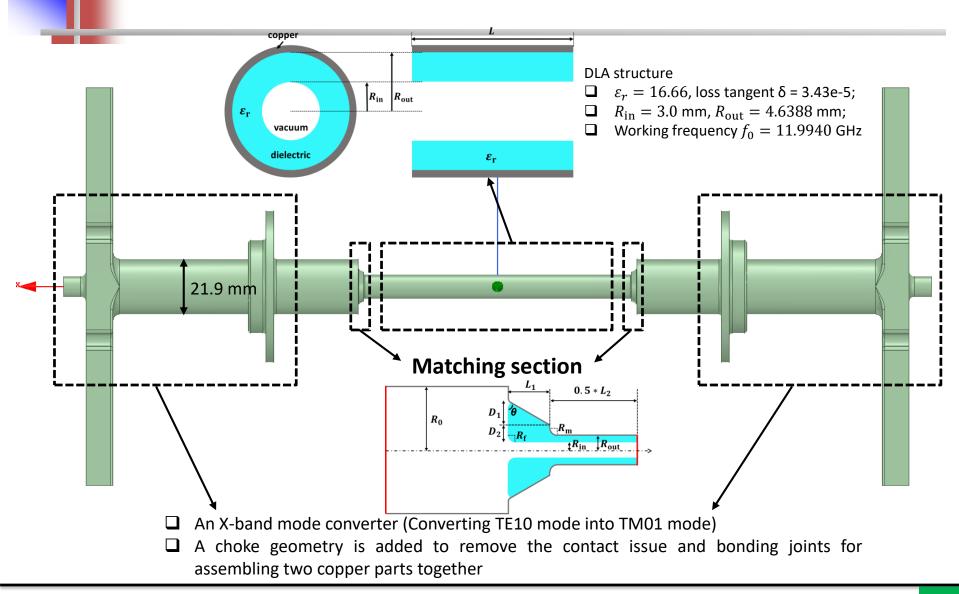
Dielectric RF property



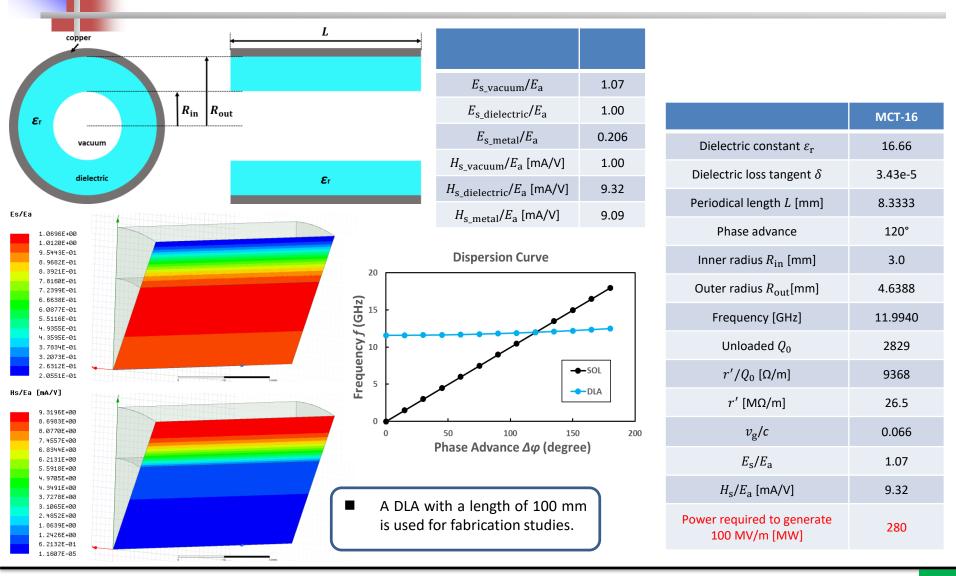
Courtesy of photo from Dr. Chunguang Jing, Euclid Techlabs.

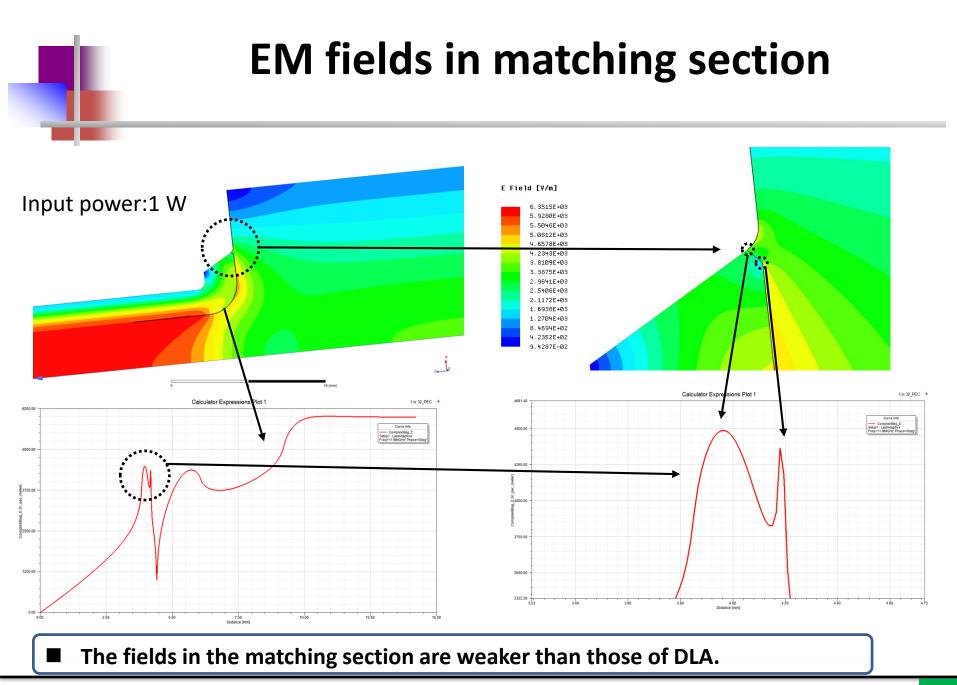
- A $TE_{01\delta}$ silver-plated resonator with a high quality factor, which is designed for testing ceramics at an X-band frequency, is used to measure the dielectric constant ε_r and loss tangent tan δ of sample coupons.
- Four dielectric coupons made from the same dielectric rods as for the fabrication of the DLA structure are measured.
- A dielectric constant ε_r = 16.66 and an ultralow loss tangent tanδ = 3.43 × 10⁻⁵ (having error bars 0.6% of the nominal value) are obtained for the RF design of the DLA structure and matching sections which follows.

An X-band DLA structure

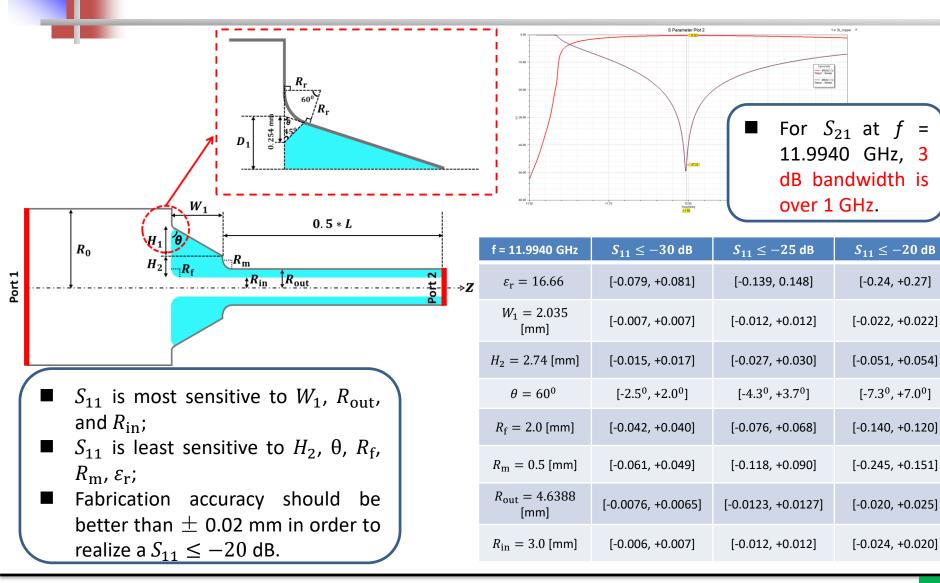


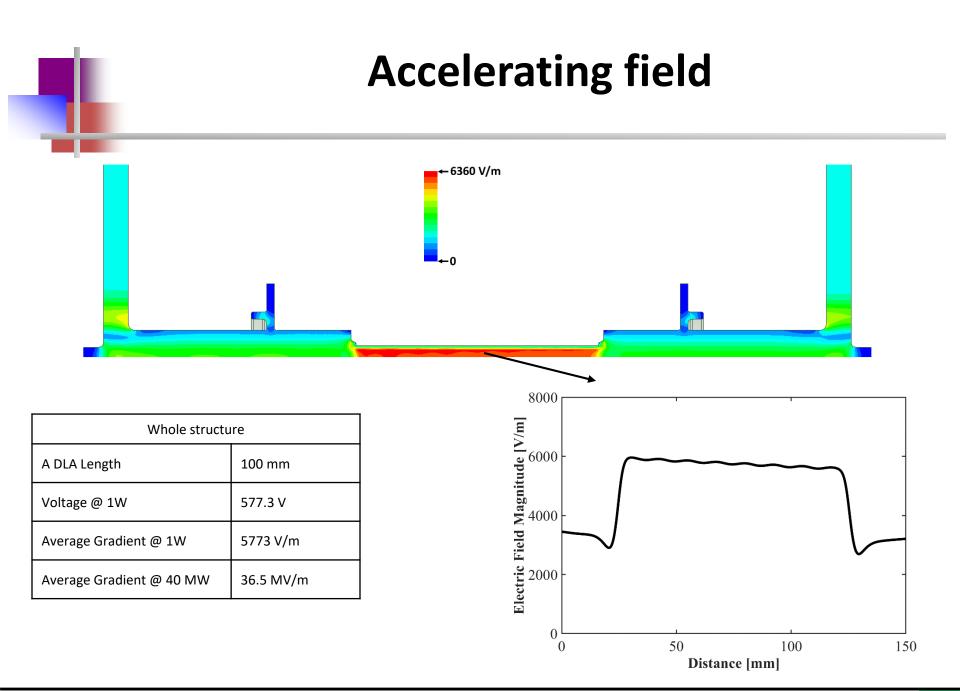
RF parameters for a DLA

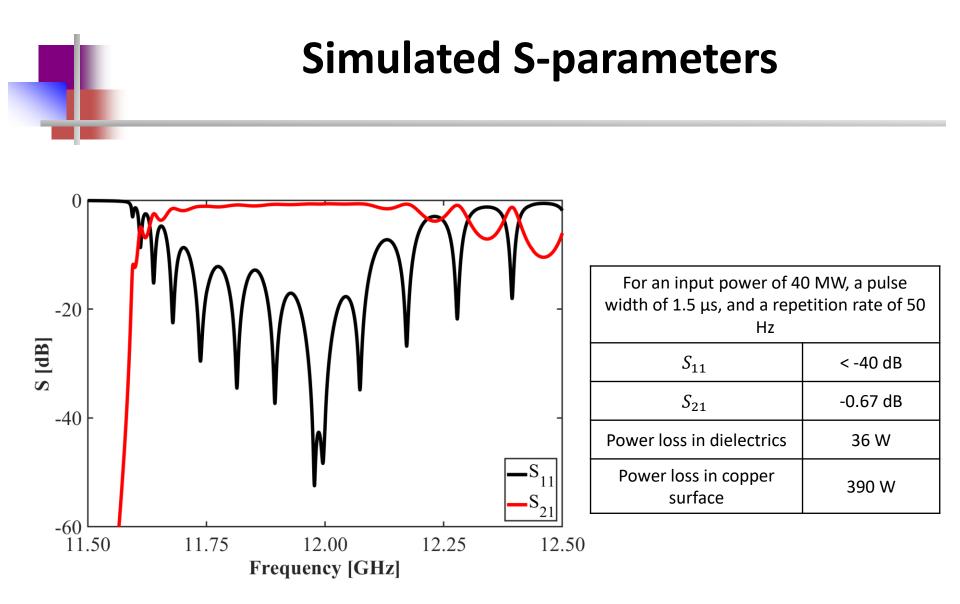




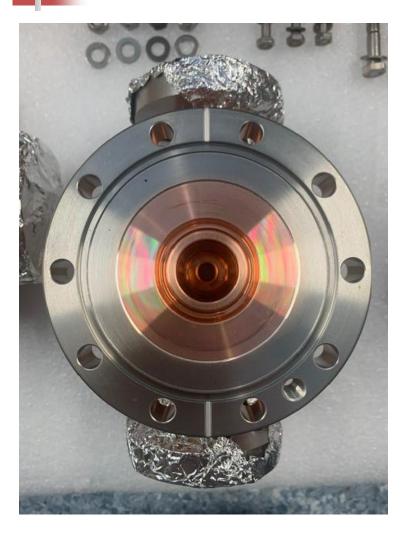
Tolerance studies

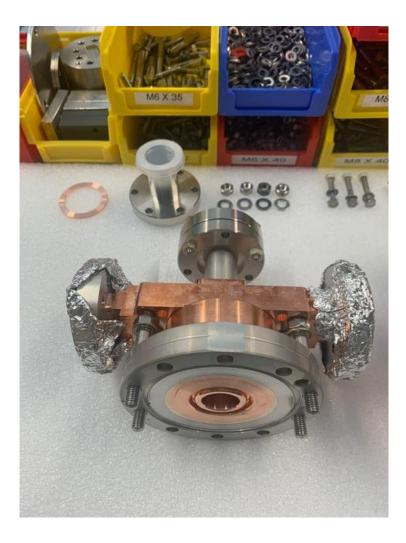




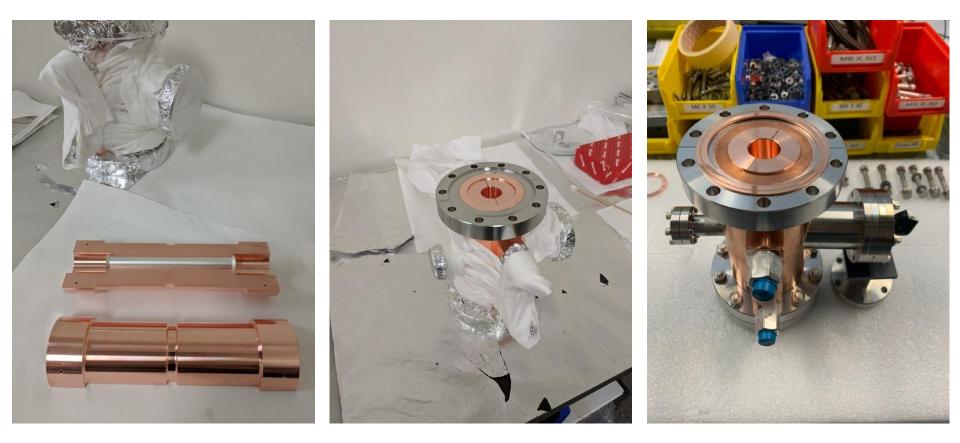


Mode converters with a choke



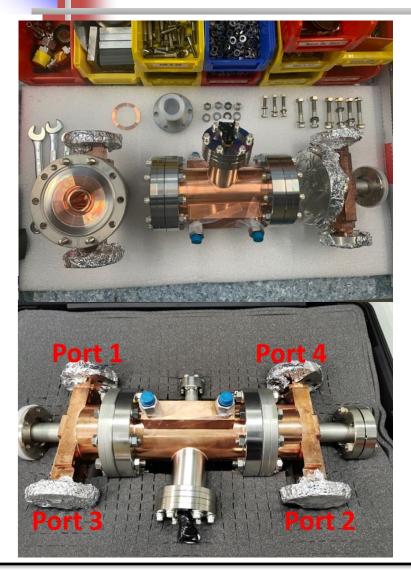


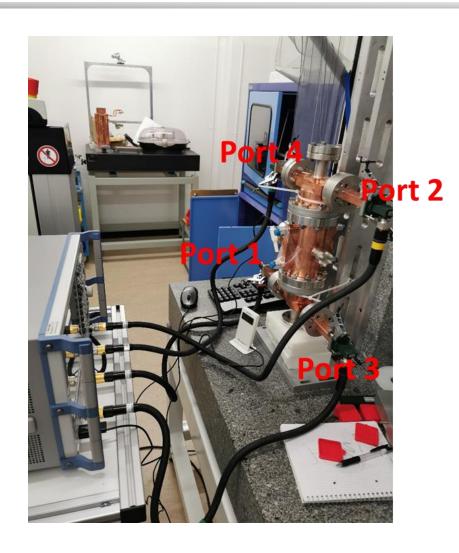
DLA structure



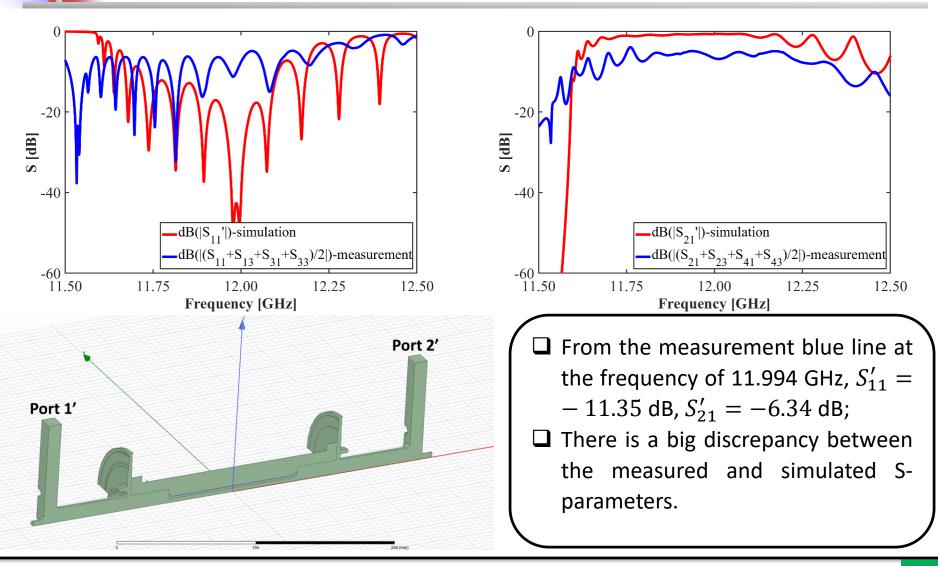
Courtesy of photos from Dr. Chunguang Jing, Euclid Techlabs.

RF Measurement on assembly of two TE10-TM01 mode converters and the DLA structure





S-parameters comparison



Summary & Outlook

- An X-band DLA structure with the TE10-TM01 mode converters and matching sections is designed, fabricated, and low-power measured.
- The fabrication error may cause the big discrepancy between measured and simulated S-parameters.

Using two power splitters for 2-port testing on the DLA structure (Large power loss results from HOMs' propagation due to the asymmetries in the 4-port testing).